What is claimed is:

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A thin film transistor-LCD, comprising: 1 1. a transparent substrate provided with at least two 2 adjacent gate electrodes; 3 a gate insulating layer on the gate electrodes; 4 a semiconductor layer in a predetermined shape on 5 the insulating layer; 6 a source/drain electrode layer on a predetermined 7 area of the transparent substrate; 8 . an insulating layer on the source/drain electrode 9 10 layer; contact hole via the insulating 11 layer, a 12 source/drain electrode layer, and qate insulating layer, exposing a part of the 13 14 surface of transparent substrate between the 15 adjacent gate electrodes; a transparent conductive layer on the transparent 16 substrate; and 17 a light-shielding matrix directly above the contact 18 19 hole. The thin film transistor-LCD as claimed in 1 2. claim 1, wherein the gate electrode 2 is a Mo-Al-Nd electrode. 3 3. The thin film transistor-LCD as claimed in 1

claim 1, wherein the source/drain electrode layer is an

Al, Al-Nb, Al-Nd, Al-Ti or Al-Si-Cu layer.

- 4. The thin film transistor-LCD as claimed in claim 1, wherein the gate insulating layer is an oxide layer formed by chemical vapor deposition.
- 5. The thin film transistor-LCD as claimed in claim 1, wherein the insulating layer is an oxide or nitride layer formed by chemical vapor deposition.
 - 1 6. The thin film transistor-LCD as claimed in 2 claim 1, further comprising a color filter a 3 predetermined distance above the transparent substrate, 4 wherein the light-shielding matrix directly above the 5 contact hole is disposed on the color filter.
 - 7. The thin film transistor-LCD as claimed in claim 1, wherein the gate electrodes are separate from the contact hole.
 - 1 8. A thin film transistor-LCD, comprising:
 - a transparent substrate provided with at least two adjacent gate electrodes;
 - a gate insulating layer on the gate electrodes;
 - a semiconductor layer in a predetermined shape on the insulating layer;
 - a source/drain electrode layer on a predetermined area of the transparent substrate;
- an insulating layer on the source/drain electrode layer;
- a contact hole, separate from the gate electrodes,

 via the insulating layer, source/drain

 electrode layer, and gate insulating layer,

- exposing a part of the surface of transparent
- substrate between the adjacent gate electrodes;
- an indium thin oxide layer on the transparent
- 17 substrate;
- a color filter provided a predetermined distance
- above the transparent substrate; and
- a light-shielding matrix on the color filter,
- directly above the contact hole.
- 9. The thin film transistor-LCD as claimed in
- 2 claim 8, wherein the gate electrode is a Mo-Al-Nd
- electrode, and the source/drain electrode layer is an Al,
- 4 Al-Nb, Al-Nd, Al-Ti or Al-Si-Cu layer.
- 1 10. The thin film transistor-LCD as claimed in
- 2 claim 8, wherein the gate insulating layer is an oxide
- layer and the insulating layer is an oxide or nitride
- 4 layer formed by chemical vapor deposition.
- 1 11. A method of fabricating a thin film transistor-
- 2 LCD, comprising:
- depositing a first metal layer on a transparent
- 4 substrate;
- 5 patterning the first metal layer to form at least
- 6 two adjacent gate electrodes;
- forming a gate insulating layer on the gate
- 8 electrodes;
- 9 forming a semiconductor layer on the insulating
- 10 layer;
- 11 patterning the semiconductor layer into a
- 12 predetermined shape;

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- depositing a second metal layer on the transparent 13 14 substrate; 15 patterning the second metal layer to form a source/drain electrode layer; 16 depositing an insulating layer on the transparent 17 substrate; 18 19 defining a contact hole via the insulating layer, 20 source/drain electrode layer, and gate
- source/drain electrode layer, and gate insulating layer, exposing a part of the surface of transparent substrate between the adjacent gate electrodes;
- depositing a transparent conductive layer on the transparent substrate; and
- forming a light-shielding matrix directly above the contact hole.
- 1 12. The method as claimed in claim 11, wherein the gate electrode is a Mo-Al-Nd electrode.
- 13. The method as claimed in claim 11, wherein the source/drain electrode layer is an Al, Al-Nb, Al-Nd, Al-3 Ti or Al-Si-Cu layer.
- 14. The method as claimed in claim 11, wherein the 2 gate insulating layer is an oxide layer formed by 3 chemical vapor deposition.
- 15. The method as claimed in claim 11, wherein the insulating layer is an oxide or nitride layer formed by chemical vapor deposition.

The method as claimed in claim 11, further 16. 1 comprising a step of providing a color filter a 2 predetermined distance above the transparent substrate, 3 wherein the light-shielding matrix directly above the 4 contact hole is disposed on the color filter. 5 The method as claimed in claim 11, wherein the 17. 1 gate electrodes are separated from the contact hole. 2 18. A method of fabricating a thin film transistor-1 LCD, comprising: 2 depositing a first metal layer on a transparent 3 . substrate; 4 5 patterning the first metal layer to form at least adjacent electrodes gate 6 bу two photolithography; 7 forming a gate insulating layer on 8 the gate 9 electrodes; forming a semiconductor layer on the insulating 10 layer; 11 12 patterning the semiconductor layer into 13 predetermined shape by photolithography; 14 depositing a second metal layer on the transparent substrate; 15 patterning the second metal layer to form a 16 source/drain 17 electrode layer by photolithography; 18 19 depositing an insulating layer on the transparent substrate; 20

- defining a hole by photolithography, 21 contact separated from the gate electrodes, via the 22 23 insulating layer, source/drain electrode layer, and gate insulating layer, exposing a part of 24 the surface of transparent substrate between 25 26 the adjacent gate electrodes; depositing an indium tin oxide 27 layer the on transparent substrate; 28 29 providing a color filter a predetermined distance 30 . above the transparent substrate, having a light-shielding matrix directly above 31 the 32 contact hole.
 - 19. The method as claimed in claim 18, wherein the gate electrode is a Mo-Al-Nd electrode; the source/drain electrode layer is an Al, Al-Nb, Al-Nd, Al-Ti or Al-Si-Cu layer.
 - 20. The method as claimed in claim 18, wherein the gate insulating layer is an oxide layer and the insulating layer is an oxide or nitride layer formed by chemical vapor deposition.